


<b>Search Notes</b>  	<b>Application/Control No.</b>  10530677	<b>Applicant(s)/Patent Under Reexamination</b>  YOSHINO ET AL.
	<b>Examiner</b>  Eoff, Anca	<b>Art Unit</b>  1795

SEARCHED			
Class	Subclass	Date	Examiner
430	270.1, 281.1, 285.1, 287.1	12/4/2007	AE
522	100, 103, 134, 135, 136, 137, 138, 139, 140, 141, 142, 143, 144, 145	12/4/2007	AE
525	530, 531	12/4/2007	AE

SEARCH NOTES		
Search Notes	Date	Examiner
Inventorship search	12/6/2007	AE
Text search in East (search history attached)	12/4/2007	AE
STIC Search		
Consulted with Primary Examiner Susan Berman regarding the search in class 522, subclasses 100, 103, 134-145	12/4/2007	AE
Consulted with Primary Examiner David Buttner regarding the search in class 525, subclasses 530, 531	12/4/2007	AE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
430	270.1, 281.1, 285.1, 287.1	12/7/2007	AE
522	100, 103, 134-145	12/7/2007	AE
525	530, 531	12/7/2007	AE